

<b>Searched</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10668010	SINHA ET AL.
	Examiner Kaplan, Hal I	Art Unit 2836

Class	SubClass	Date	Examiner
307	651	10/11/2006	HK
374	172	10/11/2006	HK
374	176	10/11/2006	HK
702	99	10/11/2006	HK
365	211	10/11/2006	HK

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Part of Paper No.: 20061011

<b>Search Notes</b>  	Application/Control No.	Applicant(s)/Patent Under Reexamination
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Notes	Date	Examiner
374/1,170,172,176,178 (consulted Gail Verbitsky)	02/14/2006	HK
702/99,130 (consulted Bryan Bui)	02/15/2006	HK
365/211,222 (consulted Amir Zarabian)	10/11/2006	HK
EAST (US-PGPUB,USPAT,USOCR,FPRS,EPO,JPO,DERWENT,IBM_TD B) - See Search History Printout	10/11/2006	HK
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